L								
	Type	T #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
	IS&R	Γ	-	("20020183990").PN.	USPAT; US-PGPUB	2003/02/24 11:02		
7	BRS	L4	2	switch same model same impedance same conductance and input same output	USPAT; US-PGPUB; DERWENT	2003/02/24 11:04		
3	BRS	L8	86	odel sam	USPAT; US-PGPUB; DERWENT			
4	BRS	L16	309		USPAT; US-PGPUB; DERWENT	2003/02/24 11:11		
5	BRS	L12	309	switch same model same input same output and I/O	USPAT; US-PGPUB; DERWENT	2003/02/24 11:19		
9	6 BRS	L20	178	circuit same model same I/O same ports	USPAT; US-PGPUB; DERWENT	2003/02/24 11:20		

	Type	Hits	Search Text	DBs	Time Stamp
17	BRS	11611	model and (integrated adj circuit) same switching	USPAT; US-PGPUB; DERWENT	2003/02/22 17:37
18	BRS	235	model and (integrated adj circuit) same switching same voltage same current and resistors	USPAT; US-PGPUB; DERWENT	2003/02/22 17:39
19	19 BRS	304	model and (integrated adj circuit) same switching same voltage same current	USPAT; US-PGPUB; DERWENT	2003/02/22 17:39
20	BRS	235	model and (integrated adj circuit) same switching same voltage same current and (resistors or resisters)	USPAT; US-PGPUB; DERWENT	2003/02/22 17:39
21	BRS	16	model and (integrated adj circuit) same switching same voltage same current and resistors and waveforms	USPAT; US-PGPUB; DERWENT	2003/02/22 17:42
22	BRS	45	model and (integrated adj circuit) same switching same voltage same current same resistors and waveforms	USPAT; US-PGPUB; DERWENT	2003/02/22 17:50
23	BRS	443	model and modeling and input same output and (integrated adj circuit) and characterization	USPAT; US-PGPUB; DERWENT	2003/02/22 17:51
24	BRS	15451	driver same circuit and (integrated adj circuit) and switching	USPAT; US-PGPUB; DERWENT	2003/02/22 17:52
25	BRS	331	driver same circuit same model and (integrated adj circuit) and switching	USPAT; US-PGPUB; DERWENT	2003/02/22 17:52
56	26 BRS	180	model same (integrated adj circuit) same switching	USPAT; US-PGPUB; DERWENT	2003/02/22 17:59
27	27 BRS	48	model same (integrated adj circuit) same switching same resistor	USPAT; US-PGPUB; DERWENT	2003/02/22 18:03

	Туре	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
65	65 BRS 312	312	(IO or I/O) same model same circuit and switching	USPAT; US-PGPUB; DERWENT; IBM_TDB	2003/08/06 14:16		
66	BRS 193	193	(IO or I/O) same model same circuit and switching and driver	me circuit and DERWENT; US-PGPUB; IBM TDB	2003/08/07 10:26		

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O Basic O Advanced  Lights Survey O Join IEEE O Establish IEEE Web Account O Access the IEEE Member Digital Library	1 Extraction of transient b buffers from IBIS Tehrani, P.F.; Yuzbe Chen; Jia Electronic Components and To Proceedings., 46th 28-31 Ma Page(s): 1009 -1015	ayuan Fang; echnology Conference, 1996.	
Print Format	[Abstract] [PDF Full-Text (50	00 KB)] IEEE CNF	
	2 The development of anal IBIS model	og SPICE behavioral mode	el based on

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[Abstract] [PDF Full-Text (368 KB)] IEEE CNF

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